



POWER AMPLIFIER WORKSHOP

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Recent advances in RF measurements systems : How to choose the good characterization tools to help the power amplifiers designers

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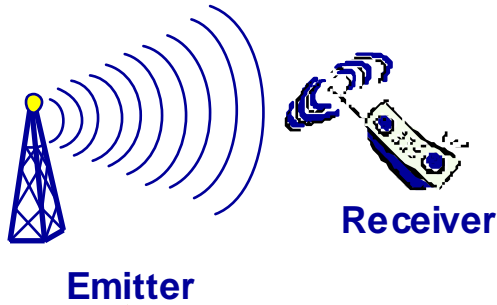
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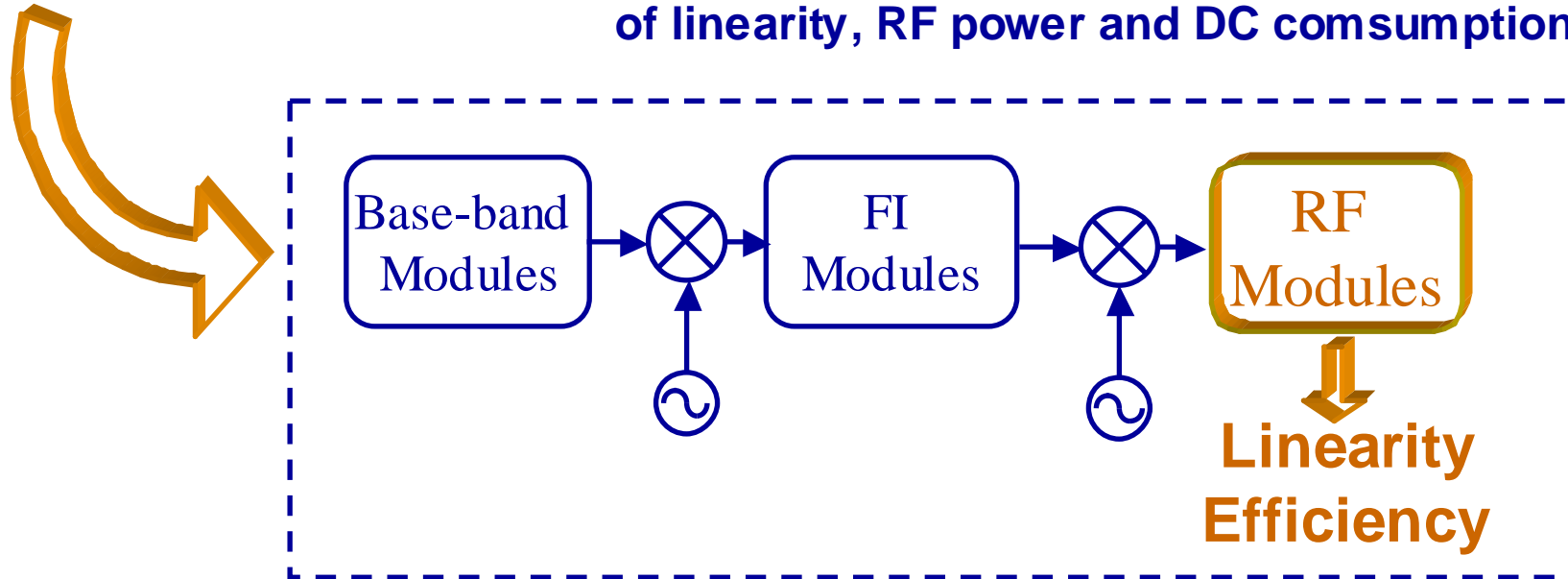
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- 1. Introduction – Classical Characterization Methods.**
- 2. RF Time-domain characterization**
- 3. Conclusion and future investigations**

➤ Telecommunication systems :



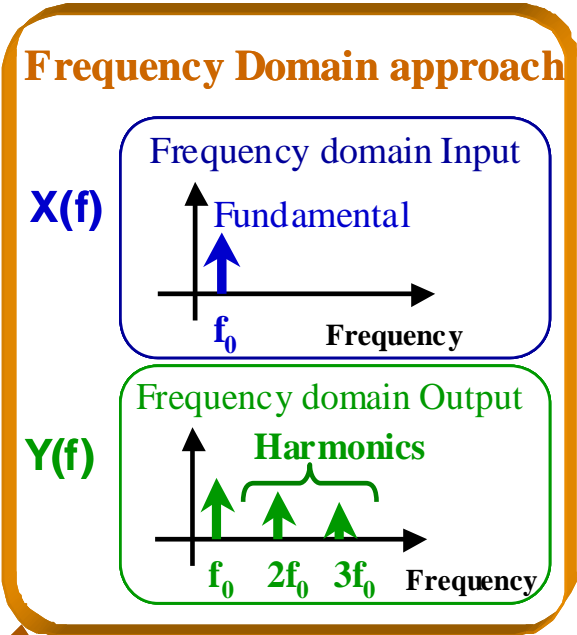
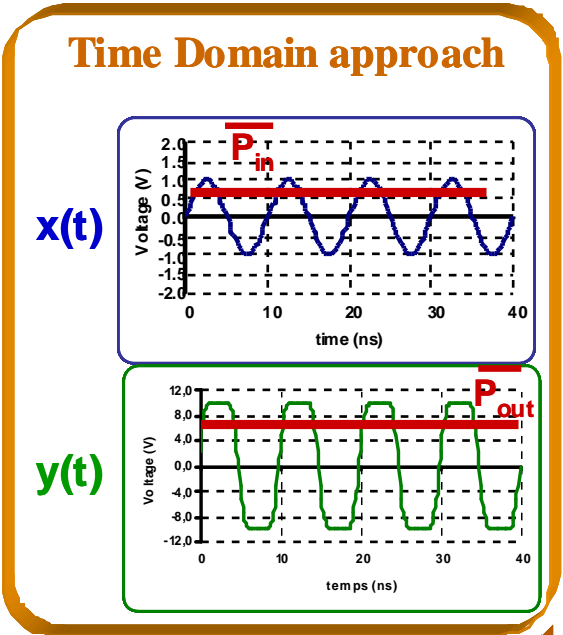
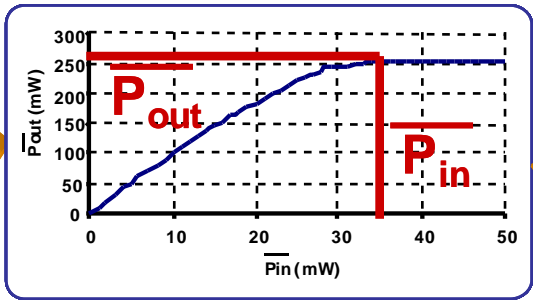
- Use of Digital complex modulations
- Base-band modules based on DSP
- Critical specifications for RF modules in terms of linearity, RF power and DC consumption.



↪ **Linearity versus efficiency optimization of power amplifier**



$x(t)$: Single tone
 \hookrightarrow **Constant envelope**



Non linear Device :

- \hookrightarrow Average Power Characteristics
- \hookrightarrow Gain Compression/expansion

\hookrightarrow **Waveform Distortions**

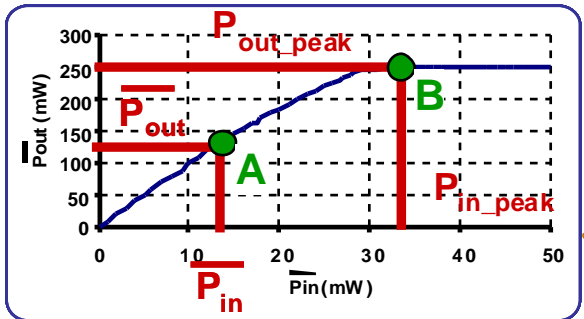
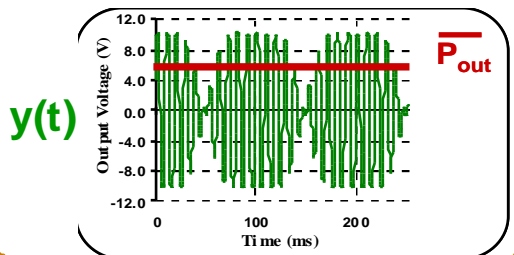
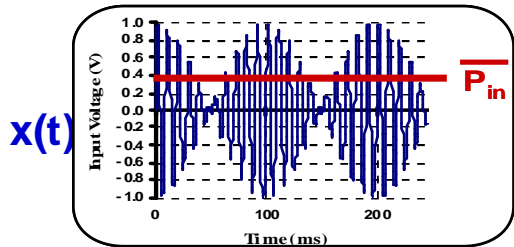
Basic correspondences to kept in mind

\hookrightarrow **Generation of harmonics**

$x(t)$: Two-tones

↪ **Non Constant envelope**

Time Domain approach

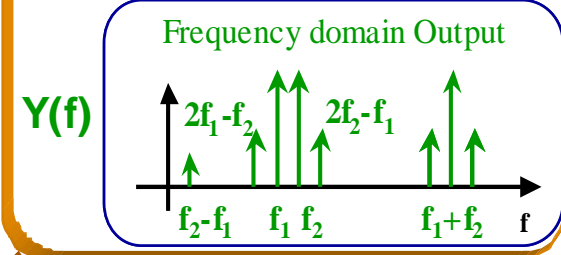
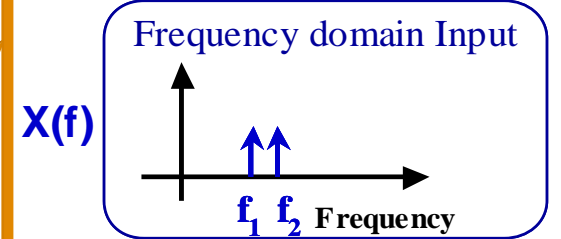


Non linear Device :

- ↪ Average Power Characteristics
- ↪ Gain Compression/expansion

↪ **Time variable instantaneous gain**

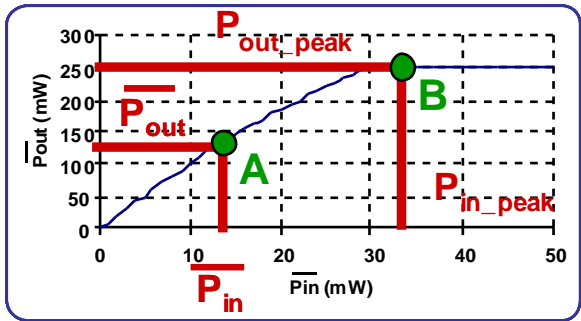
Frequency Domain approach



↪ **Carrier and envelope Distortions**

Basic correspondences to kept in mind

↪ **IMD Products**



Non linear Device :

- ↳ Average Power Characteristics
- ↳ Gain Compression/expansion

↳ Dynamic behavior

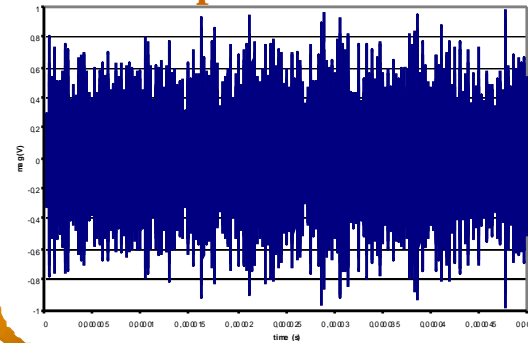
Linearity specifications :



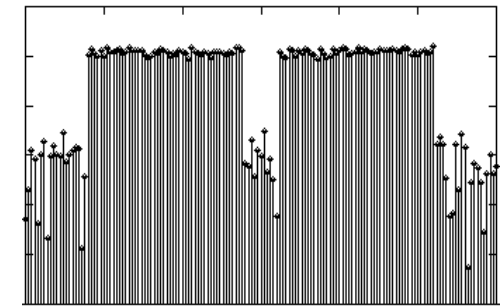
strongly depend on the application

x(t) : Complex modulated signals
↳ Non Constant envelope

Time Domain Representation



Frequency Domain Representation



Both Domain Visualization :

↳ **Average of the nonlinear phenomena difficult to distinguish and analyze.**

➤ **Complexity test signals**



➤ **difficulty of comprehension of the fundamental phenomena**

➤ Classical approach :

- ☞ Input Power Back-off ⇒ ☞ over-sized P_{as} (poor efficiency performances)
- ☞ External linearisation (Feedforward, Cartesian Feedback, ...) ⇒ ☞ Complex sub-system Designs

↘ A Posteriori Curative solutions

➤ New trends :

From optimized transistor process :

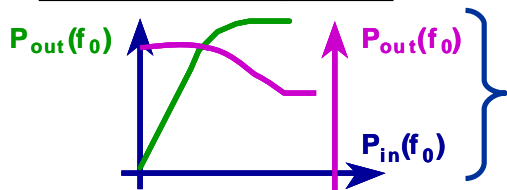
- ☞ Optimization of **Operating conditions** of transistors (RF impedances, biasing circuit topology)
- ☞ « **SMART POWER** » Design Solutions (dynamic biasing, CALLUM, adaptive pre-distortions)

↘ Characterization methods and tools are necessary to aid in :

- defining **DESIGN CRITERIA**
- implementing **PRACTICAL** and **EFFICIENT** solutions

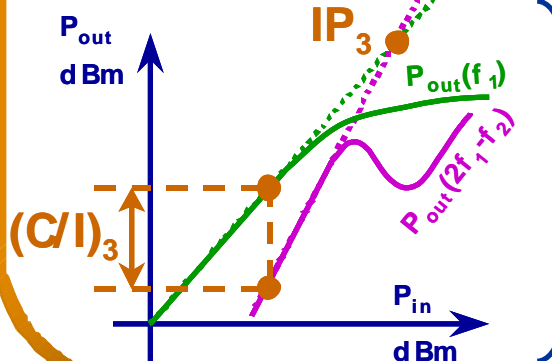
Simple test signal

☞ **CW test signal :**



**AM/AM
AM/PM
Characteristics**

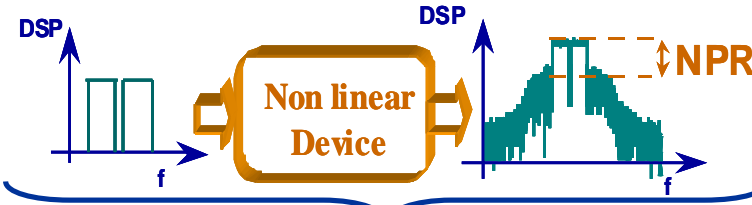
☞ **Two-tones test signal**



- IMD
- $(C/I)_3 @ P_{out}$
- IP_3

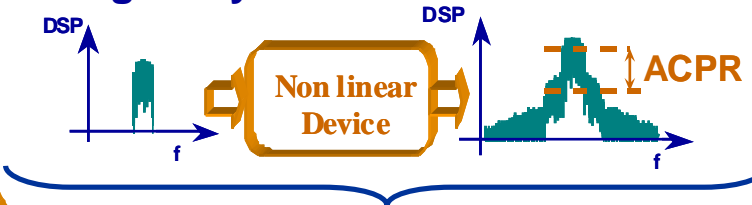
More complex test signals

☞ **Band-limited noise :**



Intermodulation noise

☞ **Digitally modulated carrier :**



Spectral regrowth

☞ **Simple test signals :** ⇨ Design methodology and criterion identification

☞ **Complex test signals :** ⇨ validation step

↪ **Needs of specific characterization tools making enable :**

☞ **Average Power measurements :**

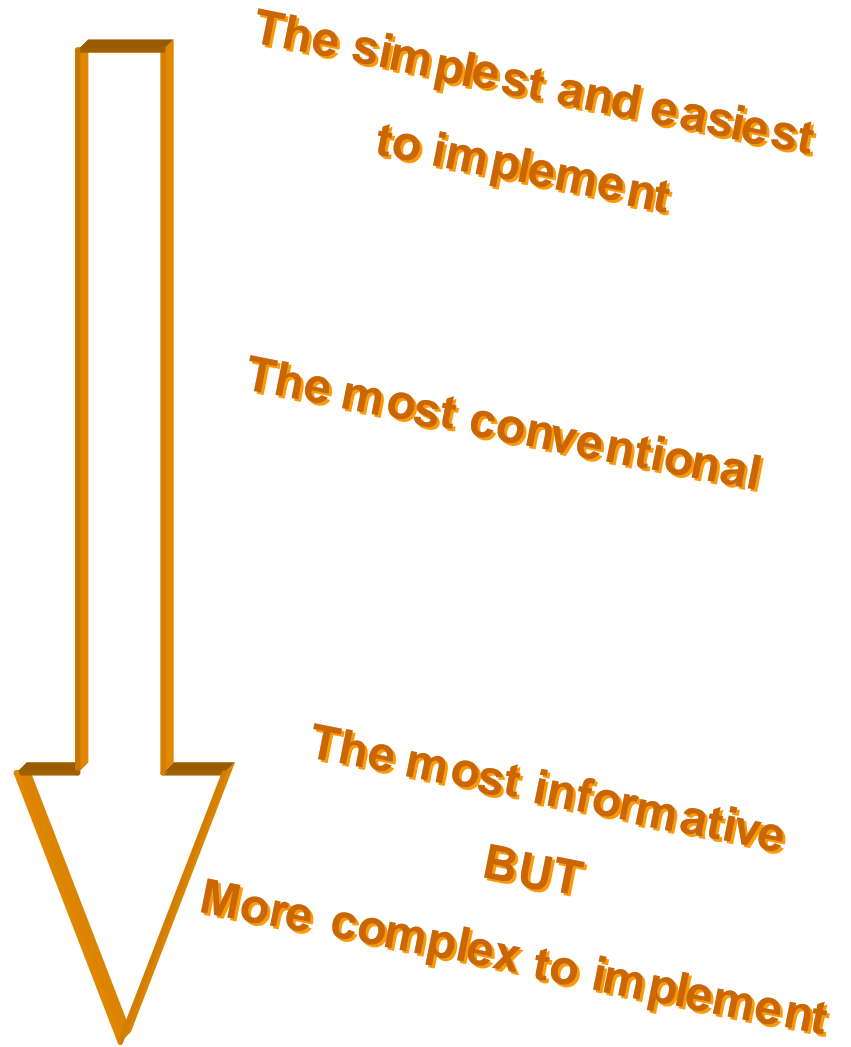
- ✓ Power Meter
- ✓ Scalar Analyzer
- ✓ Spectrum Analyzer

☞ **Frequency Domain Measurements**

- ✓ Vector Network Analyzer

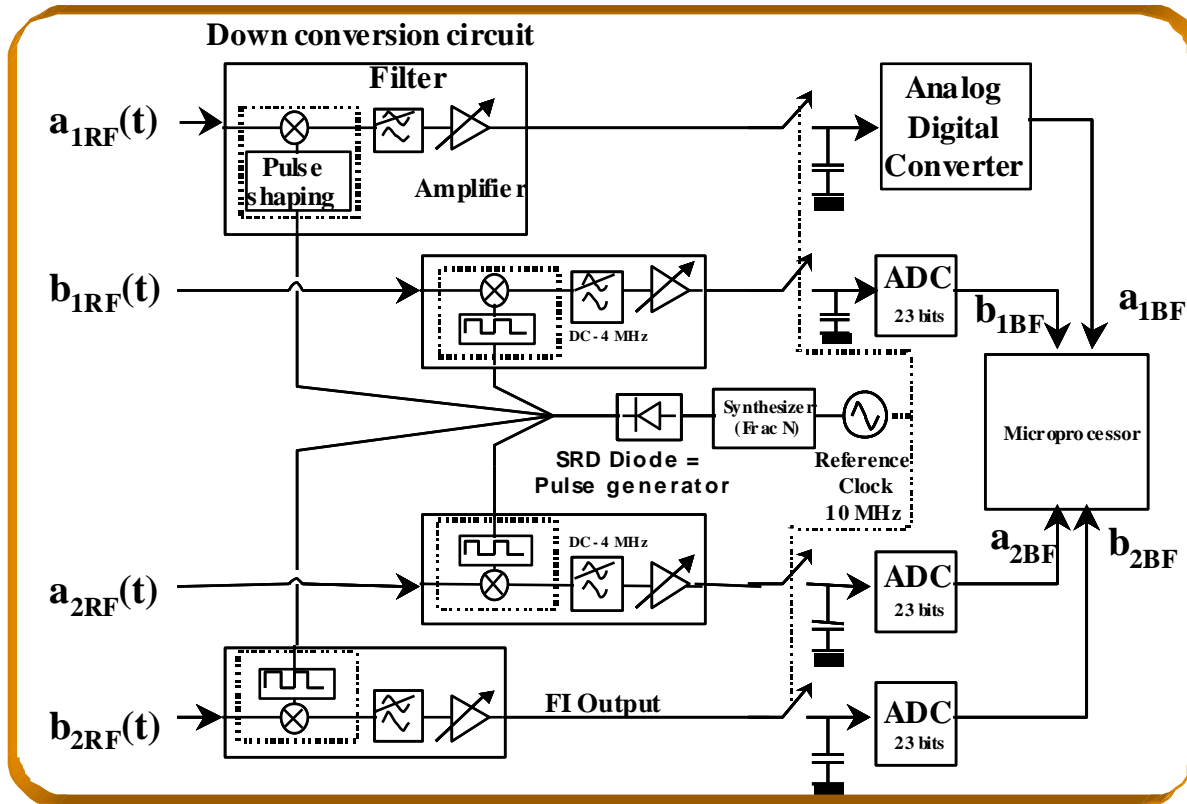
☞ **Time Domain measurements.**

- ✓ sampling Oscilloscopes
- ✓ MTA
- ✓ LSNA
- ✓ DC current and voltage probes



- 1. Introduction – Classical Characterization Methods.**
- 2. RF Time-domain characterization**
- 3. Conclusion and future investigations**

➤ Measurement Instrument : ➤ Large Signal Network Analyzer (LSNA)

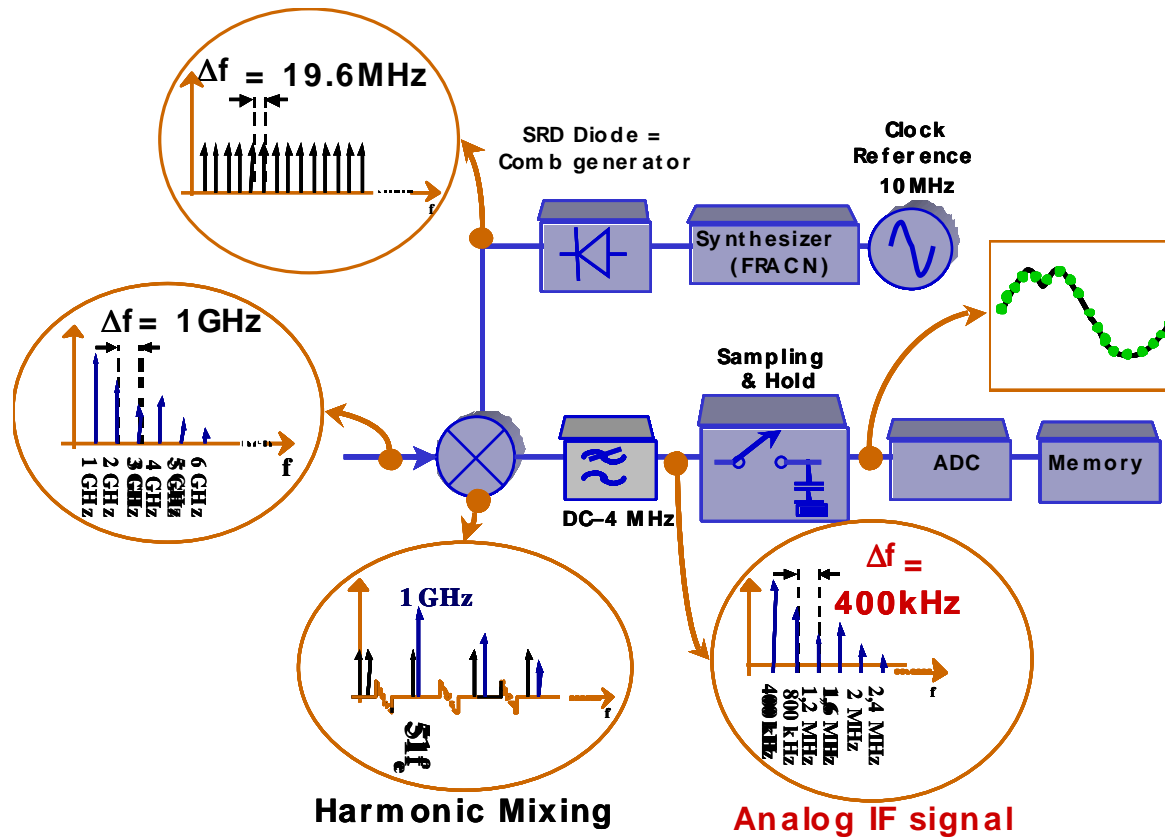


- 4 fully synchronized Channels of acquisition
- Use of harmonic repetitive Sampling Principle
- Bandwidth limitation : low pass Filter

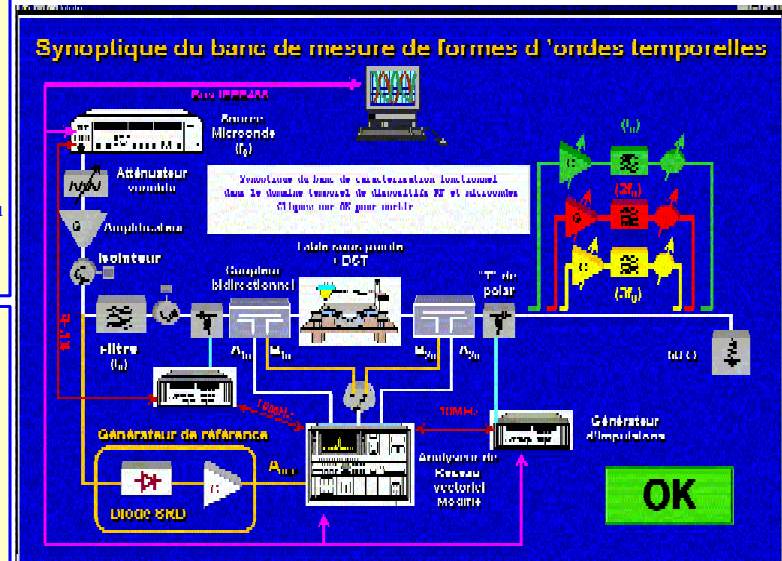
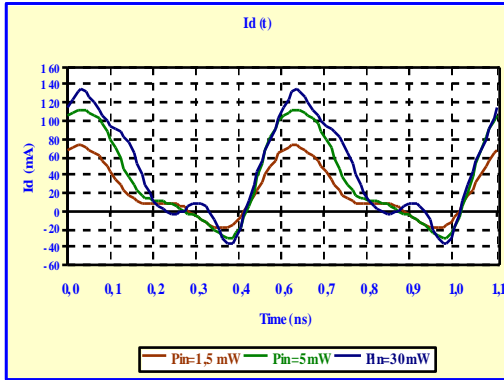
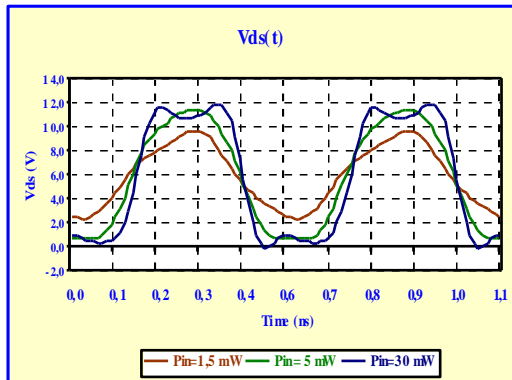
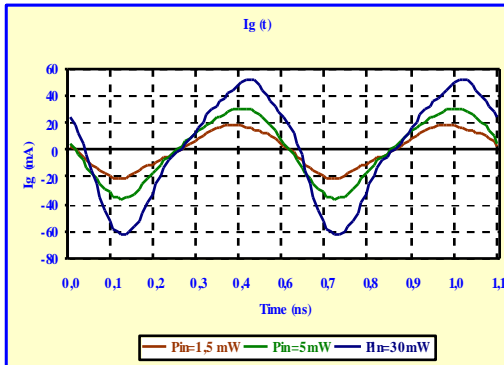
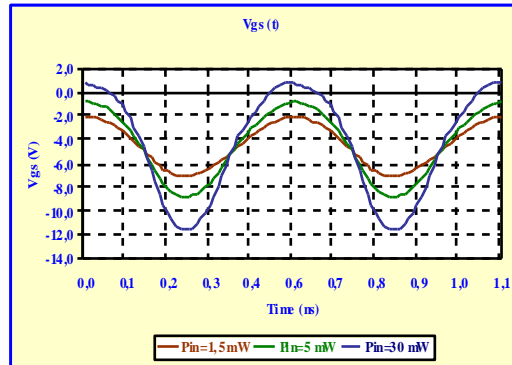
➤ Measurement Instrument : ➤ Large Signal Network Analyzer (LSNA)

➤ Analog IF signal is an equivalent image of the analog RF signal

↪ frequency translation and compression

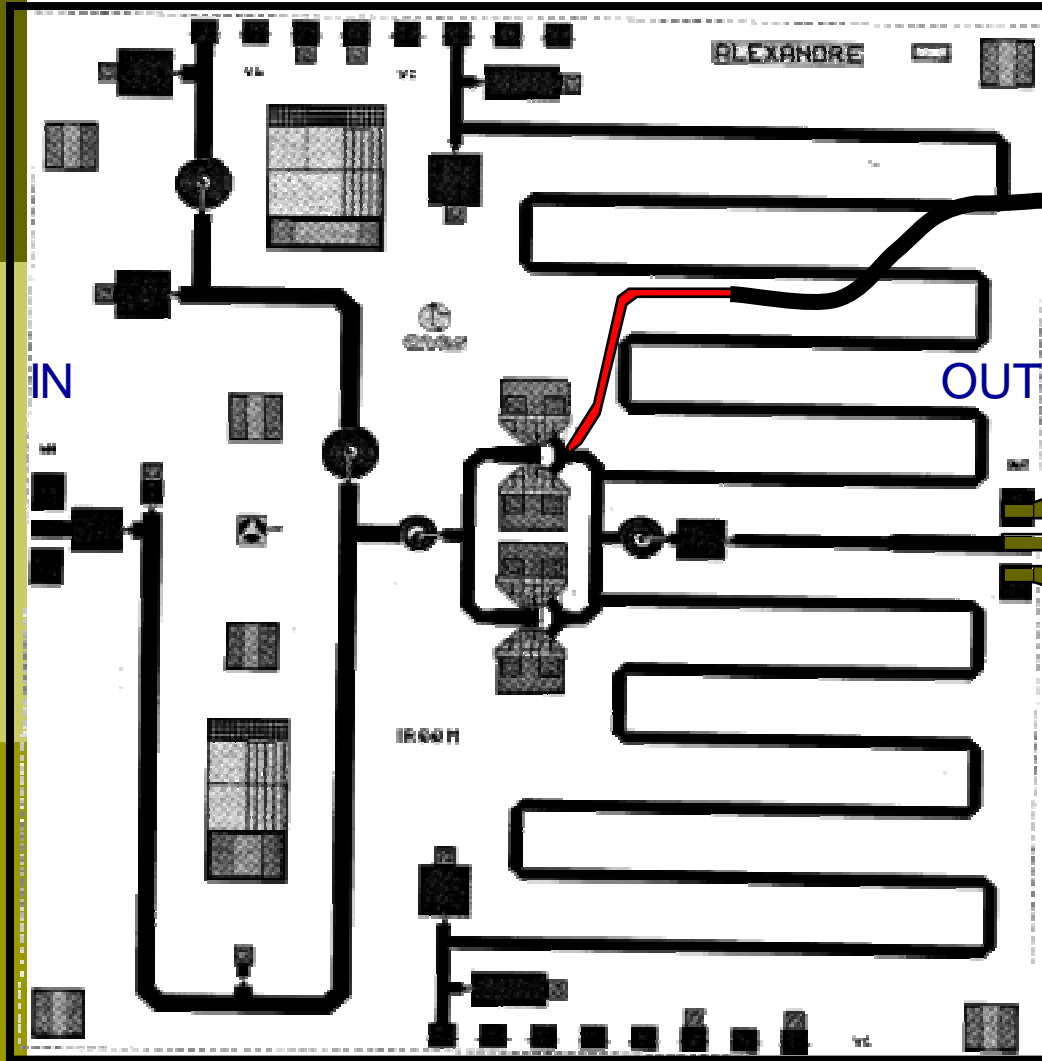


Measurement of a 8x75 μm FET
 $V_{gs0} = -4,5 \text{ V}$ - $V_{ds0} = 6 \text{ V}$ $I_{g0} = 0 \text{ mA}$ - $I_{d0} = 5 \text{ mA}$ $f_0 = 1,8 \text{ GHz}$



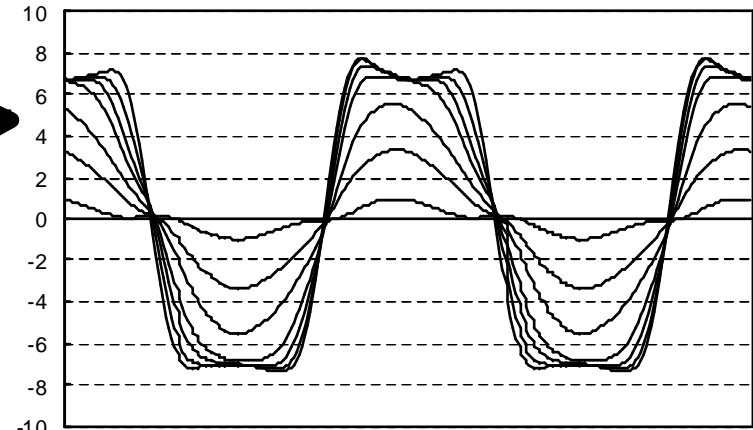
➤ **Accurate validation of non linear models of transistors**

➤ Experimental results on a non linear class F operation mode amplifier :

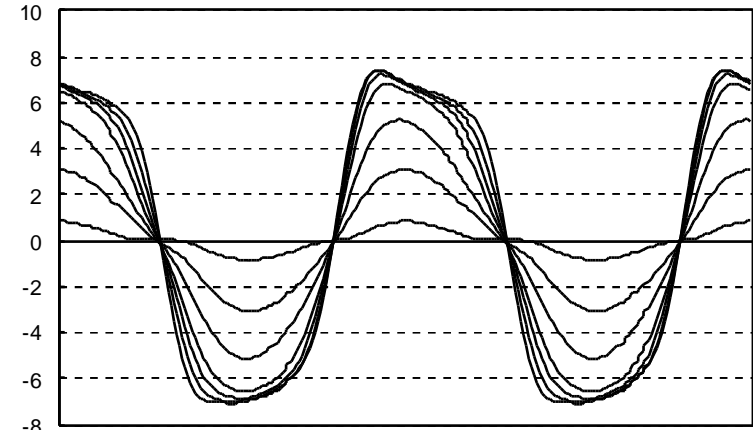


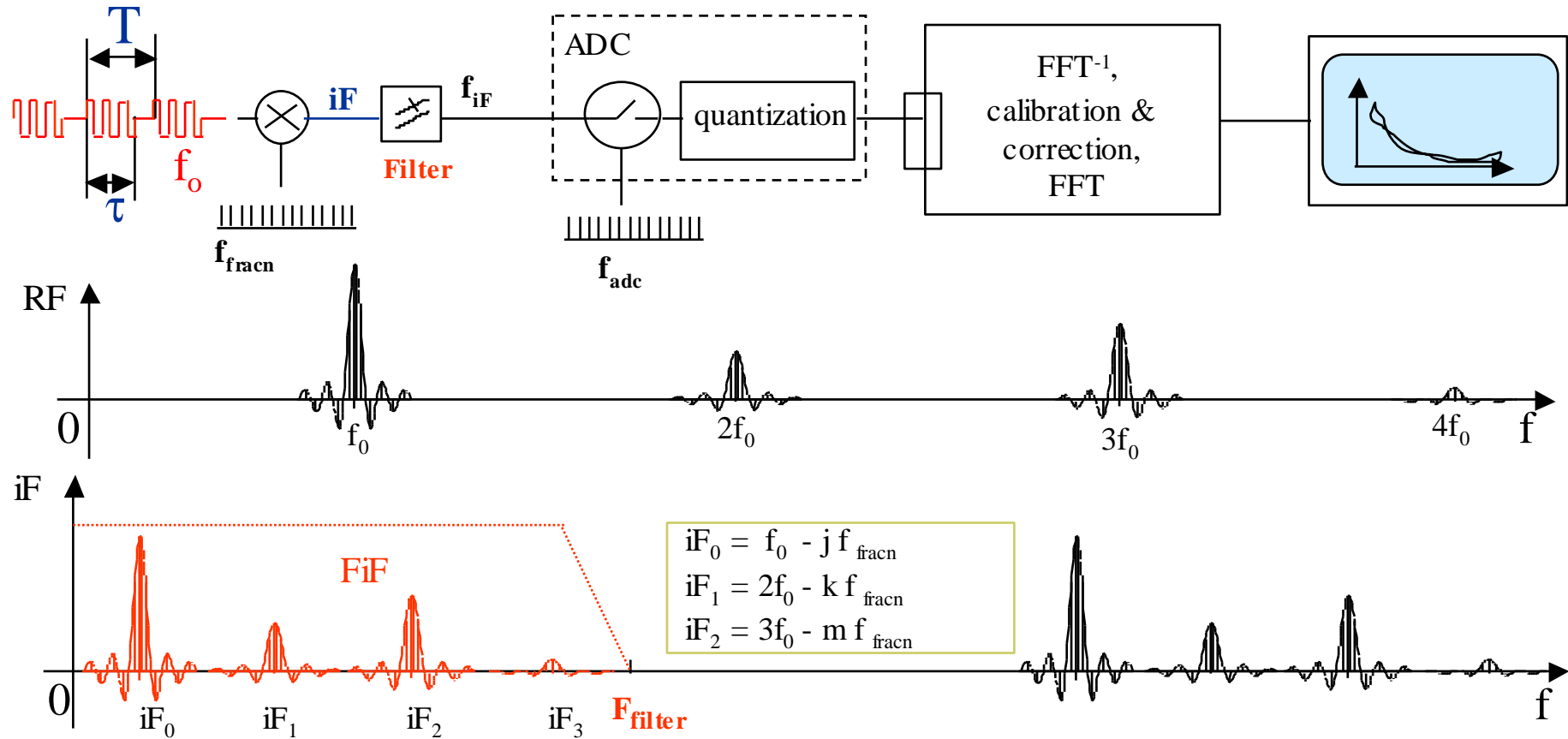
$V_{be} = 1V$

$V_{ce} = 9V$



930 ps





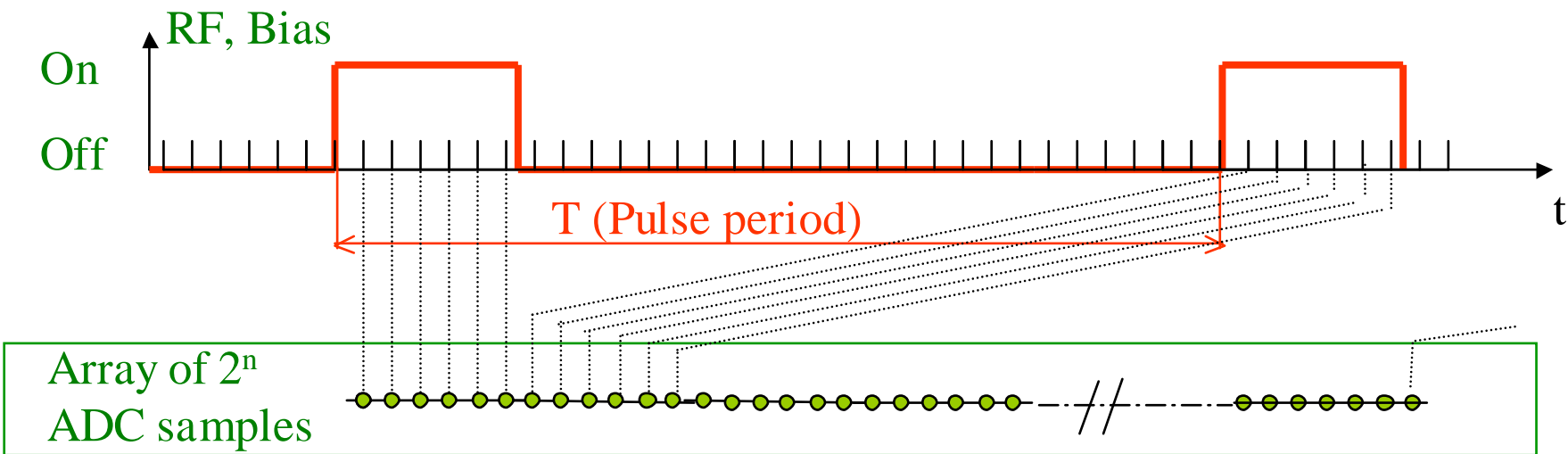
- Only the center frequency iF_i of each sinc envelope is to be considered.
- One must check that lateral (sinc) frequencies do not overlap iF_i frequencies.

➤ Limitation of the bandwidth : F_{filter}

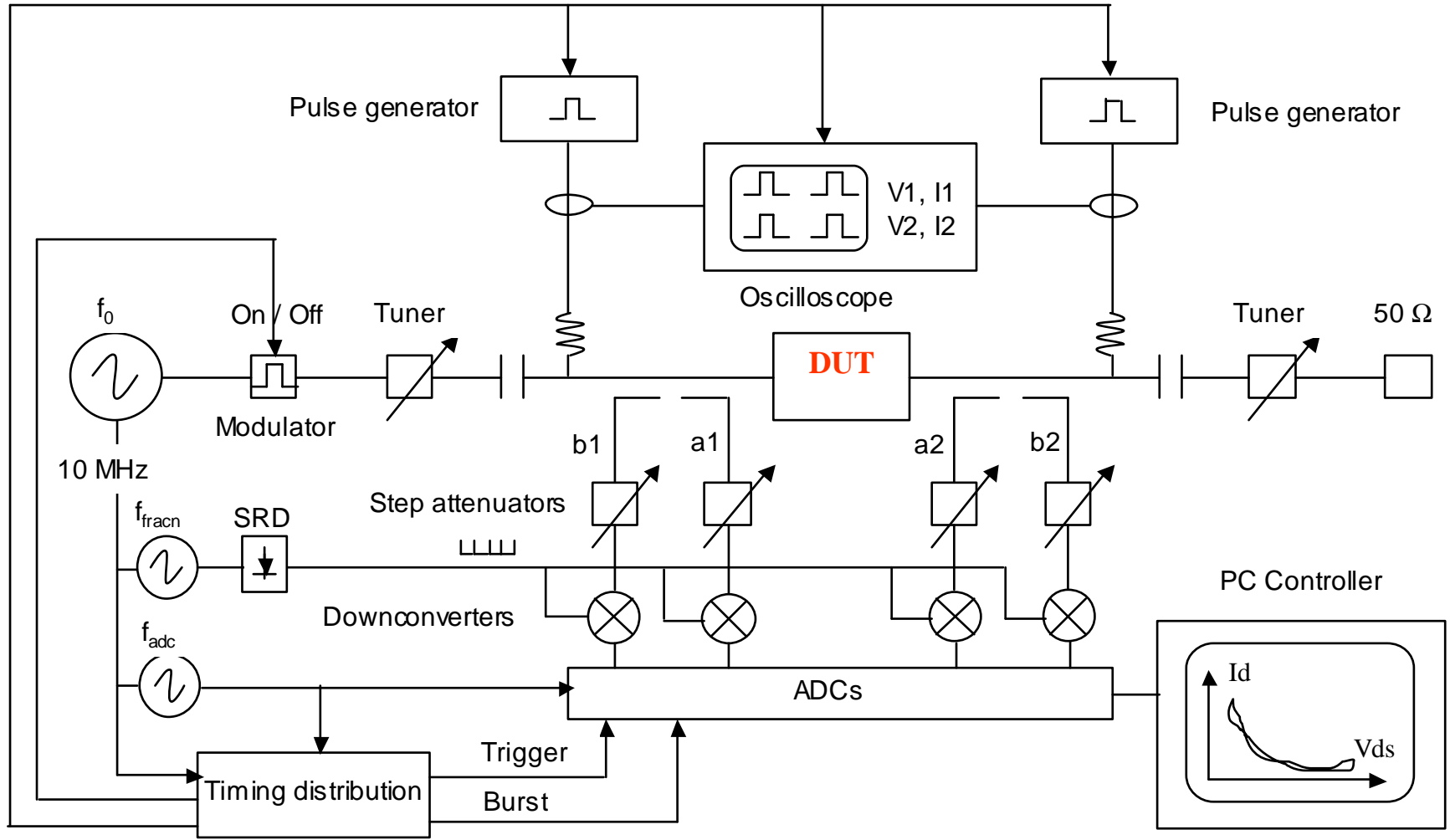
➤ Time Domain representation : ➡ Large Signal Network Analyzer (LSNA)

4 frequencies/periods are to be considered: $f_0, f_{\text{fracn}}, f_{\text{adc}}, T$ (Pulse Period)

The idea : $T = q \times \text{common period of } (f_0, f_{\text{fracn}}, f_{\text{adc}}) + \epsilon$

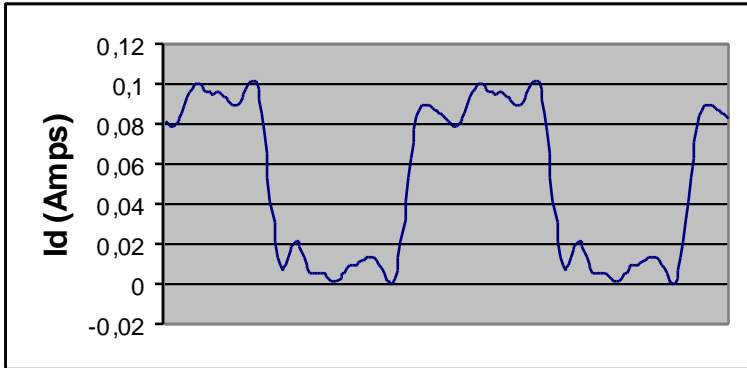
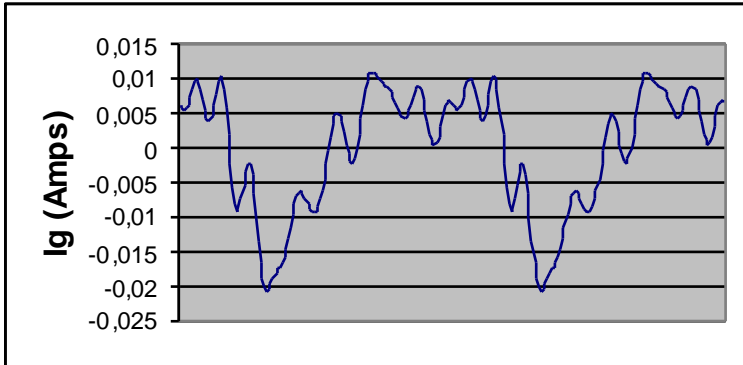
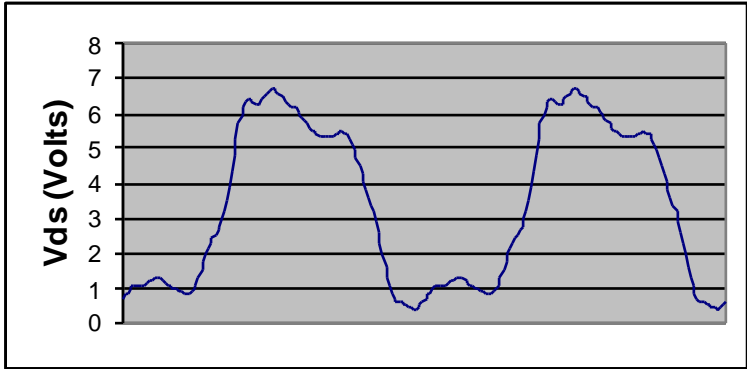
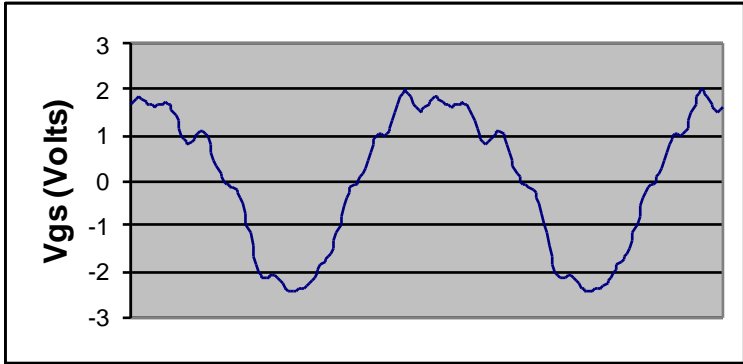


ϵ looks like the very slow phase drift of a stroboscope.



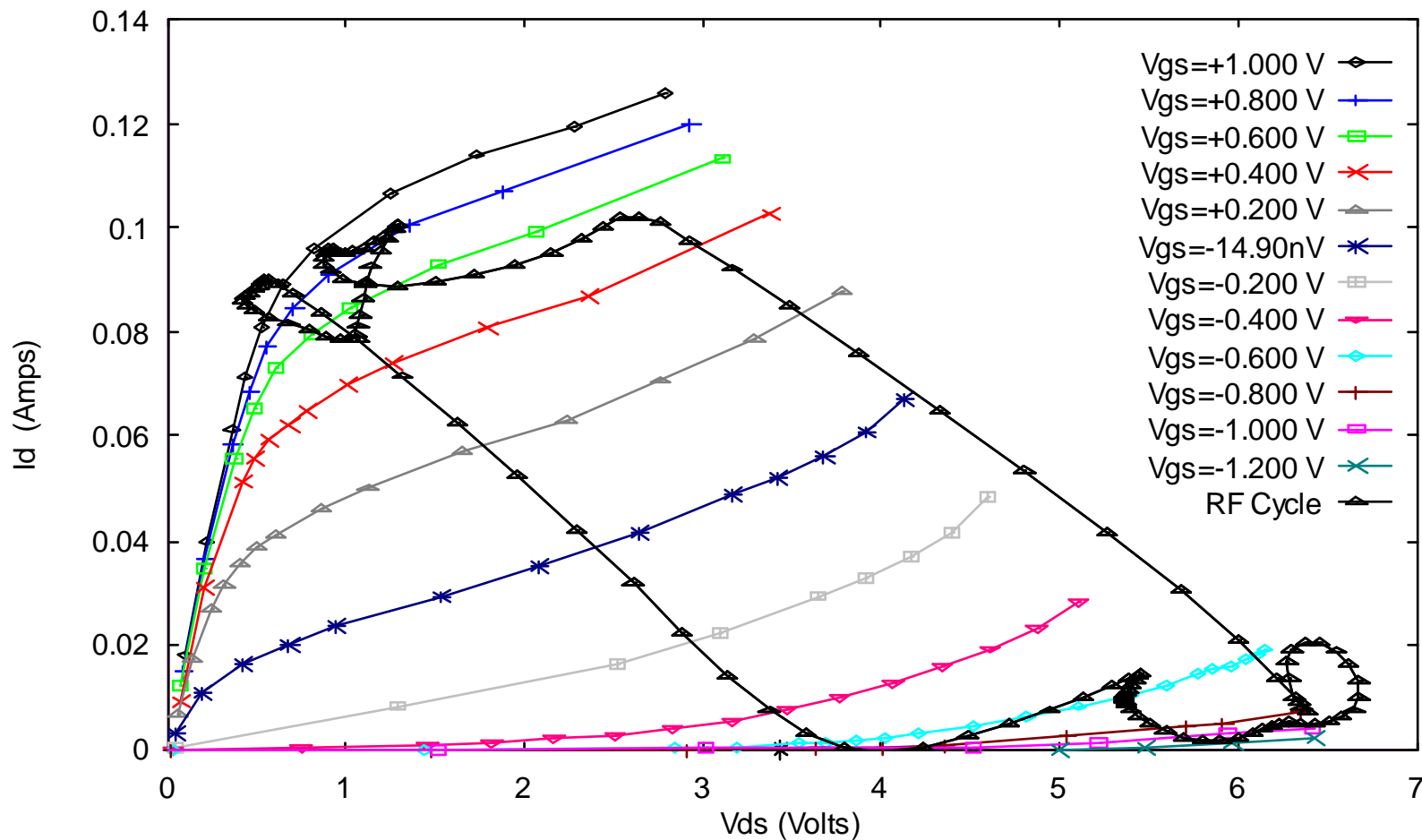
➤ All frequencies/clocks derive from the RF synthesizer high precision reference

Measurement of a 6x40 μm P-HEMT 0,15 μm - $f_0 = 1\text{GHz}$
Pulse period : 5,3125 μs , Pulse duration 400ns, pulsed bias and pulsed RF

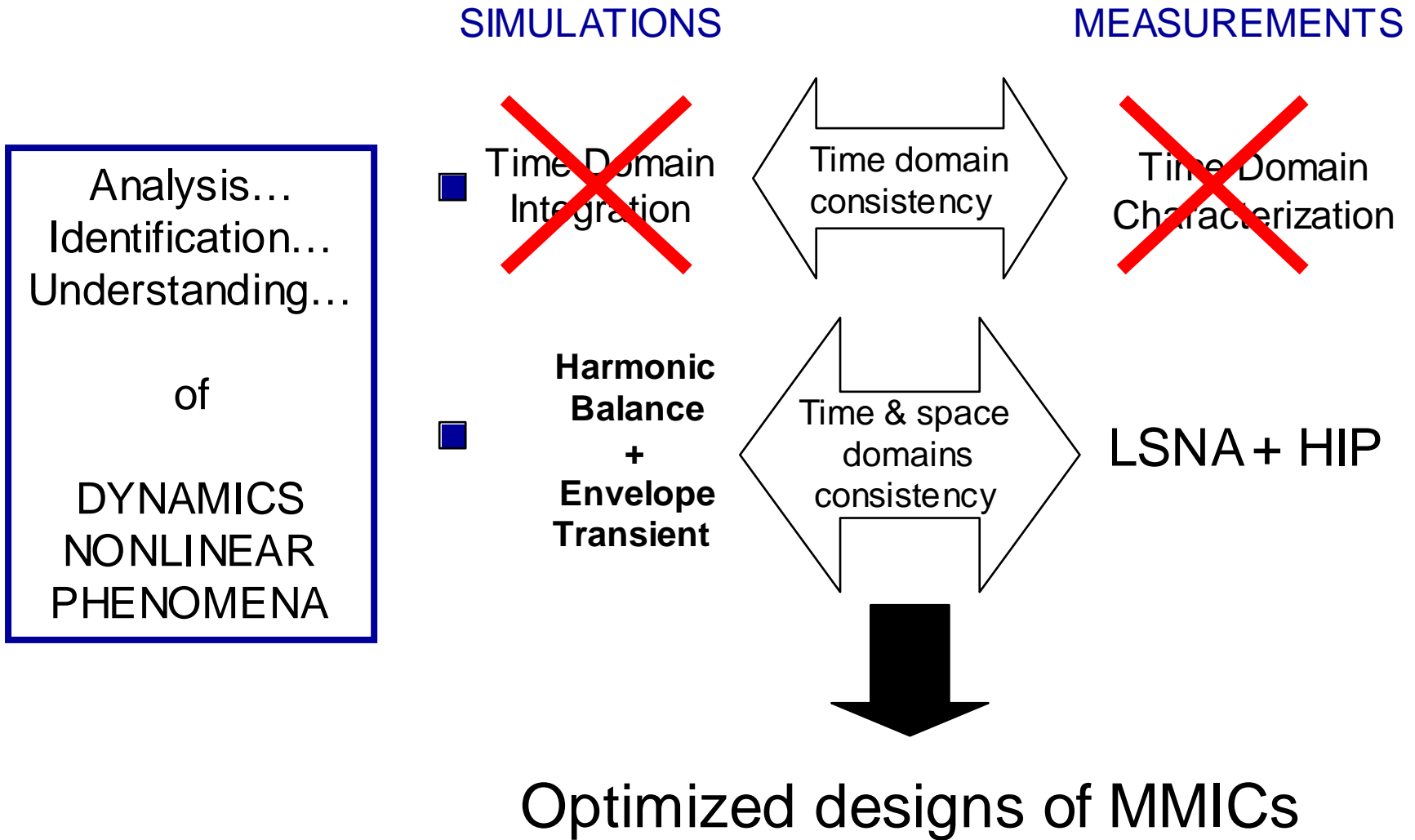


Measurement of a 6x40 μm P-HEMT 0,15 μm - $f_0 = 1\text{GHz}$
Pulse period : 5,3125 μs , Pulse duration 400ns, pulsed bias and pulsed RF

Ta 0.15 624 AA17 BIAS $V_{gs} = -0.796\text{ V}$, $V_{ds} = +3.432\text{ V}$, $I_d = +0.112\text{ mA}$

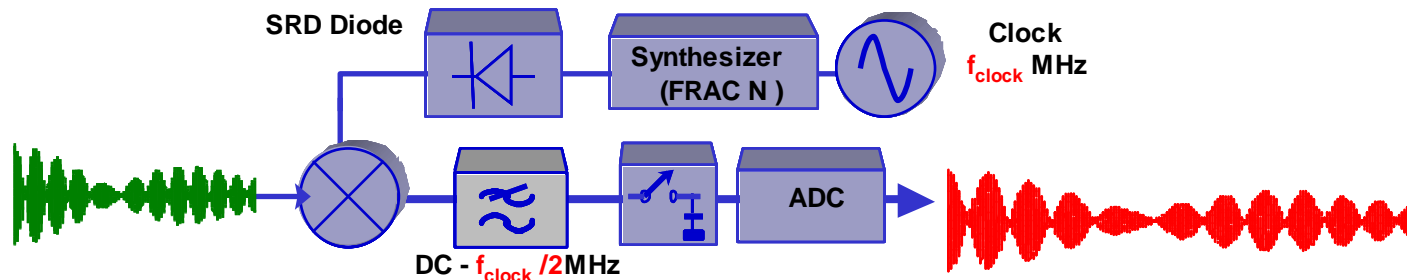


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➤ **New large Signal characterization with modulated signals**

✓ Evolution of the LSNA to the characterization of RF complex signals



Challenges:

- Definition of a new calibration procedure
- Definition of a new phase reference standards for modulated signals (multicarrier signals)